

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0094763	05-2004	Agnello et al.	257/055
*	В	US-2003/0077882	04-2003	Shih et al.	438/478
*	С	US-2002/0168802	11-2002	Hsu et al.	438/149
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
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	i	US-			
	J	US-			
	K	US-			
	ш	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000203023 A	07-2000	Japan	ITSUSHIKI, KAIHEI	
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NON-PATENT DOCUMENTS

	NOT ALL DOGGLATO					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Huang, F.Y., "Effect of strain transfer on critical thickness for epitaxial layers grown on compliant substrate," 22 May 2000, Applied Physics Letters, Volume 76, Number 21, pp 3046-3048.				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.